



OTA TEST REPORT

Applicant	Shanghai High-Flying Electronics Technology Co., Ltd
Product	Low Power 2.4GWi-Fi6 + BLE Module
Model	HF-LPT6200
Report No.	Y2211A1164-T1V1
Issue Date	March 13, 2023

TA Technology (Shanghai) Co., Ltd. tested the above equipment in accordance with the requirements in **ANSI/IEEE Std 149-2021.** The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Xn Ying

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Kei

Approved by: Xu Kai

TA Technology (Shanghai) Co., Ltd. Building 3, No.145, Jintang Rd, Pudong Shanghai, P.R.China

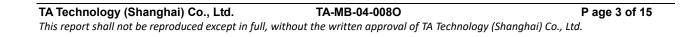
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TABLE OF CONTENTS

1.	Test La	aboratory	4
	1.1.	Notes of the Test Report	4
	1.2.	Test facility	4
	1.3.	Testing Location	4
	1.4.	Laboratory Environment	5
2.	Genera	al Description of Equipment under Test	6
	2.1.	Applicant and Manufacturer Information	6
	2.2.	General information	6
	2.3.	Test Date	6
	2.4.	Received Date	6
	2.5.	Applied Standards	7
3.	Test C	onditions	8
	3.1.	Test Configuration	8
	3.2.	Test Measurement	8
4.	Test R	esults	
	4.1.	Gain and Efficiency	9
	4.2.	Voltage Standing Wave Ratio (VSWR) & Antenna S11 & Smith Chart	10
5.		nent List	
ANNEX	x A: 3-D	Pattern Plots	12
	X B: Th	e EUT Appearance and Test Configuration	13
	B.1 EL	IT Appearance	13
	B.2 Int	ernal photo	14
	B.3 Te	st Configuration	15

Version	Revision description	Issue Date		
Rev.0	Initial issue of report.	January 9, 2023		
Rev.1	Update information.	March 13, 2023		
Note: This revised report (Report No. Y2211A1164-T1V1) supersedes and replaces the previously issued report (Report No. Y2211A1164-T1). Please discard or destroy the previously issued report and dispose of it accordingly.				





1. Test Laboratory

1.1. Notes of the Test Report

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1.2. Test facility

A2LA (Certificate Number: 3857.01)

TA Technology (Shanghai) Co., Ltd. has been listed by American Association for Laboratory Accreditation to perform measurement.

1.3. Testing Location

Company:	TA Technology (Shanghai) Co., Ltd.
Address:	Building 3, No.145, Jintang Rd, Pudong Shanghai, P.R.China
City:	Shanghai
Post code:	201201
Country:	P. R. China
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Fax:	+86-021-50791141/2/3-8000
Website:	http://www.ta-shanghai.com
E-mail:	xukai@ta-shanghai.com



1.4. Laboratory Environment

Temperature	Min. =19°C,Max. = 25°C		
Relative humidity	Min. =40%, Max. =72%		
Shield effect	0.7-6GHz > 100dB		
Ground resistance	<0.5Ω		



2. General Description of Equipment under Test

2.1. Applicant and Manufacturer Information

Applicant Name	Shanghai High-Flying Electronics Technology Co., Ltd		
Applicant addressBuilding 17, No.1500 Zu Chongzhi Road,Pudong District, 20 Shanghai, China			
Manufacturer Name Shanghai High-Flying Electronics Technology Co., Ltd			
Manufacturer address	Building 17, No.1500 Zu Chongzhi Road,Pudong District, 201203, Shanghai, China		

2.2. General information

EUT Description					
Product Name: Low Power 2.4GWi-Fi6 + BLE Module					
Model	HF-LPT6200				
HW Version:	V2.0				
SW Version:	V1.0				
Antenna Type:	Internal Antenna				
Antenna Manufacturer:	Shanghai High-Flying Electronics Technology Co., Ltd				
Test Frequency:	2412MHz ~ 2472MHz				
applicant. All indications of Pass/Fa	om the applicant to TA and the information of the EUT is declared by the ail in this report are opinions expressed by TA Technology (Shanghai) retations and/or observations of test results. Measurement Uncertainties				

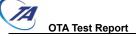
were not taken into account and are published for informational purposes only.

2.3. Test Date

The test is performed on November 25, 2022.

2.4. Received Date

The sample was received on November 14, 2022.



2.5. Applied Standards

According to the specifications of the manufacturer, it must comply with the requirements of the following standards:

Test Method: ANSI/IEEE Std 149-2021





3. Test Conditions

3.1. Test Configuration

Great-Circle-Cut method is used to measure the antenna 3D GAIN of EUT in OTA qualified anechoic chamber. Equipment Under Test (EUT) geometry centre vertical projection at the centre of platform, the distance from EUT to measurement antenna is 5m.

3.2. Test Measurement

Spherical coordinate system

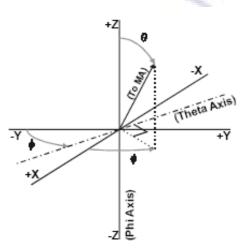
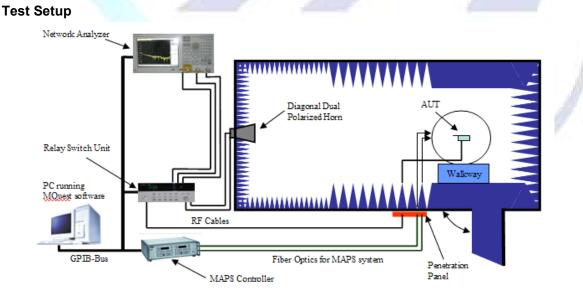




Figure 1 Test coordinate system

Note: Theta is from 0~180 degree. Phi is from 0~360. Rotate the EUT and record the Data, the step of rotation is 15 degree.



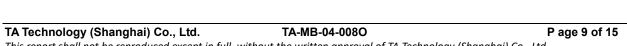
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4. Test Results

4.1. Gain and Efficiency

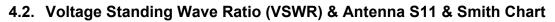
Test State	Frequency (MHz)	Efficiency (%)	Gain (dBi)	Note
	2412	49.39	0.75	
Free Space	2442	49.66	0.52	/
1	2472	49.87	0.53	

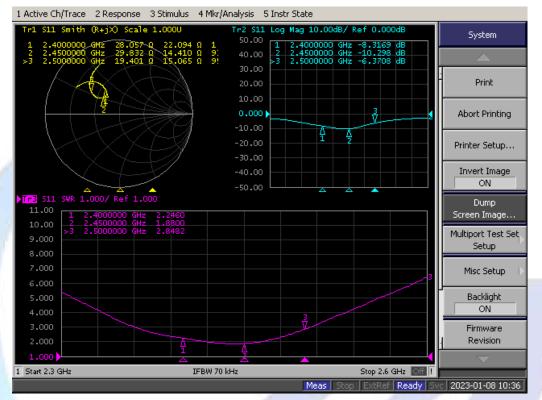


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OTA Test Report

1A





Frequency (MHz)	2400	2450	2500	
VSWR	2.2460	1.8800	2.8482	



Report No: Y2211A1164-T1V1

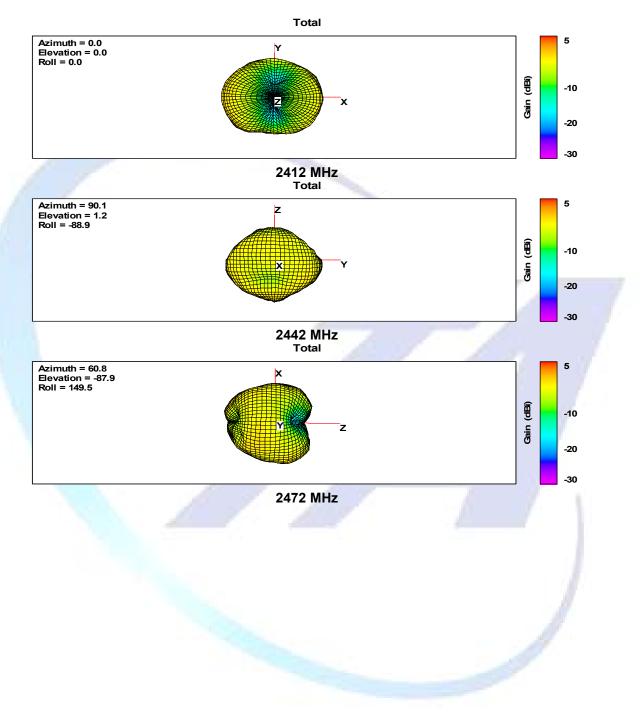
5. Equipment List

Type of Equipment	Manufacture	Model Number	S/N	Calibration Date	Expiration Time
Anechoic Chamber	ETS	AMS-8500	CT-001157- 1219	2020-05-17	2025-05-16
Test Software	ETS	EMQuest™	REV 1.0.9	-	-
EMCenter_Switch Control System	ETS	7006/7001	00059957/M Y42001152	-	-
Diagonal Dual Polarized Horn	ETS	ETS 3164-04	00062743	2020-04-14	2025-04-13
Communication TX/RX Antenna on turntable	ETS	taoglas WDMP.2458.A	100214H000 088A	-	-
Network Analyzer	Keysight	E5071B	MY42404014	2022-05-14	2023-05-13





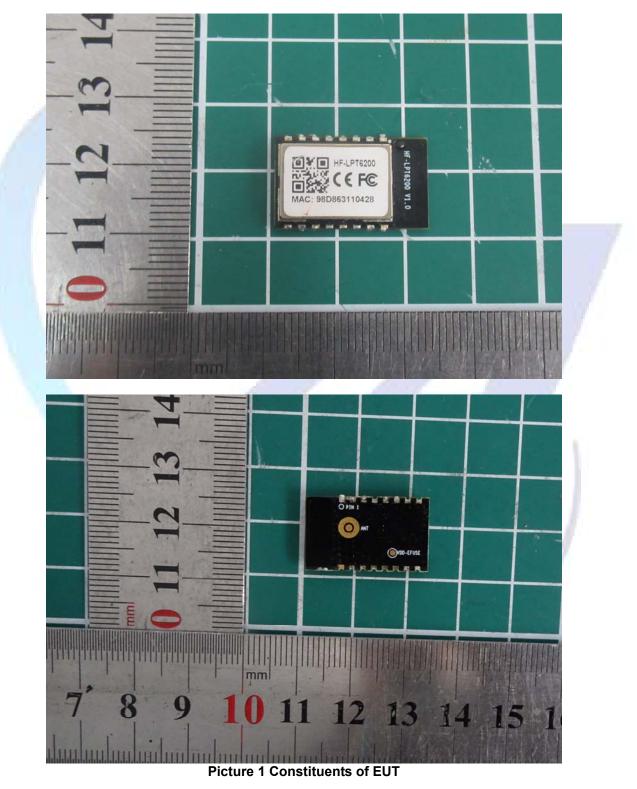
ANNEX A: 3-D Pattern Plots



OTA Test Report

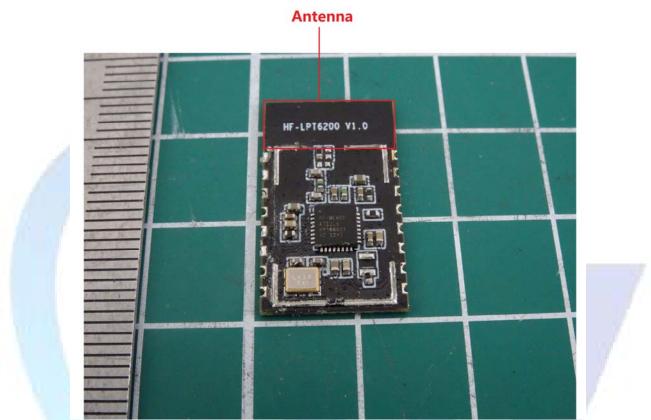
ANNEX B: The EUT Appearance and Test Configuration

B.1 EUT Appearance



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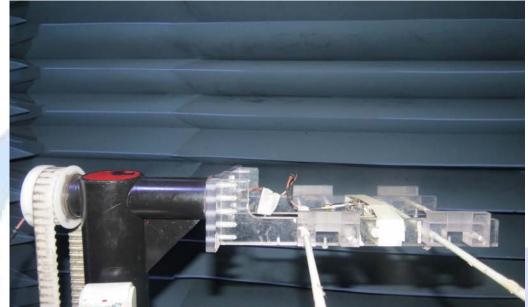




Picture 2 Antenna location



B.3 Test Configuration



Picture 3 Test Setup

******END OF REPORT ******